## IRL530STRR



# N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>(BR)DSS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)				
100	0.100 at V <sub>GS</sub> = 10 V	20				

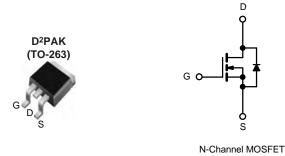
#### FEATURES

- TrenchFET<sup>®</sup> Power MOSFET
- 175 °C Junction Temperature
- Low Thermal Resistance Package
- 100 % Rg Tested

#### **APPLICATIONS**

• Isolated DC/DC Converters





ABSOLUTE MAXIMUM RATINGS Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	100			
Gate-Source Voltage	V <sub>GS</sub>	± 20	V		
Continuous Drain Current ( $T_1 = 175 \text{ °C}$ )	T <sub>C</sub> = 25 °C		20		
Continuous Drain Current (1j = 175°C)	T <sub>C</sub> = 125 °C	I <sub>D</sub>	16	_	
Pulsed Drain Current		I <sub>DM</sub>	70	A	
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	20		
Single Pulse Avalanche Energy <sup>b</sup>	L = 0.1 mm	E <sub>AS</sub>	200	mJ	
Mauiaum Daura Diasia stia sh	T <sub>C</sub> = 25 °C	P	105		
Maximum Power Dissipation <sup>b</sup>	T <sub>A</sub> = 25 °C <sup>d</sup>	- P <sub>D</sub> -	3.75	- W	
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Limit	Unit				
Junction-to-Ambient	PCB Mount (TO-263) <sup>d</sup>	R <sub>thJA</sub>	40	°C/W				
Junction-to-Case (Drain)		R <sub>thJC</sub>	0.4	C/VV				

Notes:

a. Package limited.

b. Duty cycle  $\leq$  1 %.

c. See SOA curve for voltage derating.

d. When Mounted on 1" square PCB (FR-4 material).

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{DS} = 0 V, I_{D} = 250 \mu A$	100			V	
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1		3	v	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
		$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μΑ	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = 100 V, $V_{GS}$ = 0 V, $T_{J}$ = 125 °C			50		
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 175 \text{ °C}$			250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	120			А	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A		0.100		Ω	
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	$V_{GS}$ = 10 V, $I_{D}$ = 20 A, $T_{J}$ = 125 °C		0.110			
		$V_{GS}$ = 10 V, $I_{D}$ = 20 A, $T_{J}$ = 175 °C		0.120			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 20 A	25			S	
Dynamic <sup>b</sup>	•						
Input Capacitance	C <sub>iss</sub>			950		pF	
Output Capacitance	C <sub>oss</sub>	$V_{GS}$ = 0 V, $V_{DS}$ = 25 V, f = 1 MHz		280			
Reverse Transfer Capacitance	C <sub>rss</sub>			110			
Total Gate Charge <sup>c</sup>	Qg				28	nC	
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS}$ = 100 V, $V_{GS}$ = 10 V, $I_{D}$ = 65 A			4.8		
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>				15		
Gate Resistance	Rg		0.5	1.7	3.3	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			8			
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = 100 V, R <sub>L</sub> = 1.5 $\Omega$		120		- ns	
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$\rm I_D \cong 65$ A, $\rm V_{GEN}$ = 10 V, $\rm R_g$ = 2.5 $\Omega$		25			
Fall Time <sup>c</sup>	t <sub>f</sub>			50		1	
Source-Drain Diode Ratings and Cha	aracteristics 7	$\Gamma_{\rm C} = 25 \ {}^{\circ}{\rm C}^{\rm b}$					
Continuous Current	ا <sub>S</sub>				65	٨	
Pulsed Current	I <sub>SM</sub>				140	A	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	$I_{F} = 65 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$		1.0	1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			130	200	ns	
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>	I <sub>F</sub> = 50 A, di/dt = 100 A/μs		8	12	А	
Reverse Recovery Charge	Q <sub>rr</sub>			0.52	1.2	μC	

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Notes:

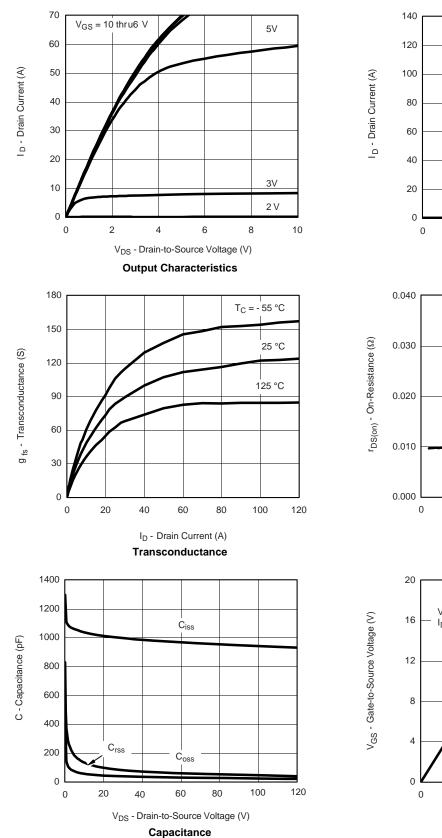
a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

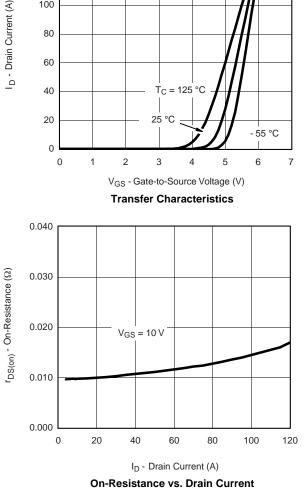
c. Independent of operating temperature.

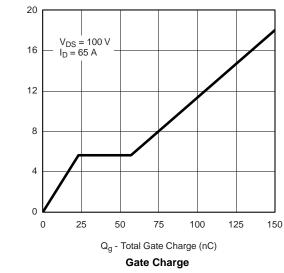
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





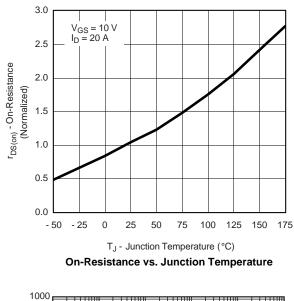
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

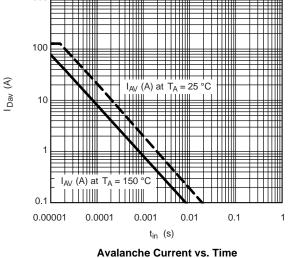


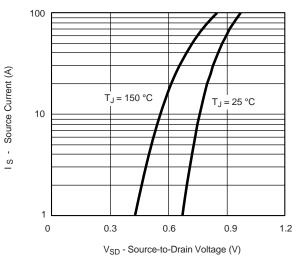




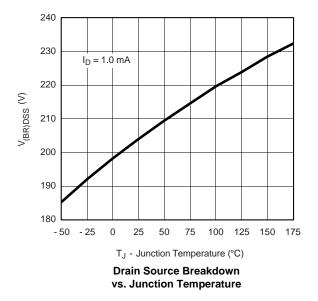
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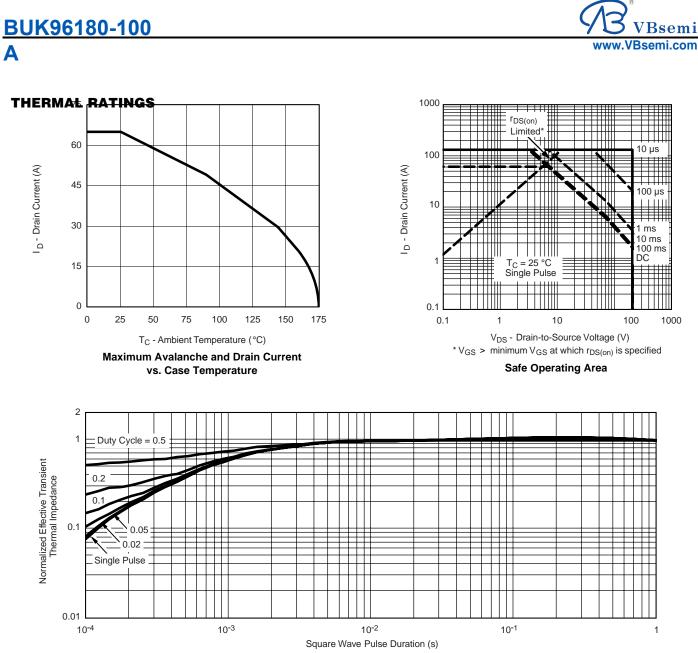






Source-Drain Diode Forward Voltage

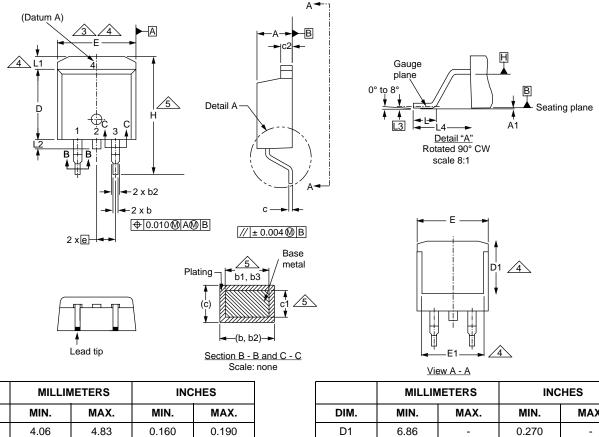




Normalized Thermal Transient Impedance, Junction-to-Case



#### **TO-263AB (HIGH VOLTAGE)**



DIM.	MIN.	MAX.	MIN.	MAX.		DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.06	4.83	0.160	0.190		D1	6.86	-	0.270	-	
A1	0.00	0.25	0.000	0.010		E	9.65	10.67	0.380	0.420	
b	0.51	0.99	0.020	0.039		E1	6.22	-	0.245	-	
b1	0.51	0.89	0.020	0.035		е	2.54	2.54 BSC		0.100 BSC	
b2	1.14	1.78	0.045	0.070		Н	14.61	15.88	0.575	0.625	
b3	1.14	1.73	0.045	0.068		L	1.78	2.79	0.070	0.110	
с	0.38	0.74	0.015	0.029		L1	-	1.65	-	0.066	
c1	0.38	0.58	0.015	0.023		L2	-	1.78	-	0.070	
c2	1.14	1.65	0.045	0.065		L3	0.25 BSC		0.010 BSC		
D	8.38	9.65	0.330	0.380		L4	4.78	5.28	0.188	0.208	
	ECN: S-82110-Rev. A, 15-Sep-08 DWG: 5970										
Notos											

#### Notes

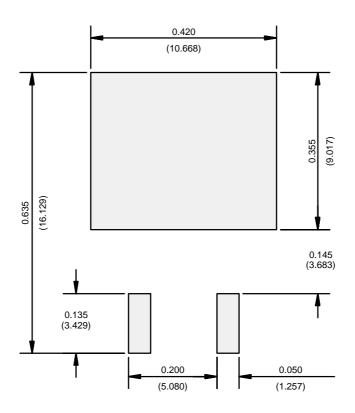
- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).

- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.

<sup>3.</sup> Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.



### RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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